

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/719,484	CHEN ET AL.	
Examiner	Art Unit	
David F Martinez	2181	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
710	38	2/28/2007	DM	
714	43	2/28/2007	DM	
709	224	2/28/2007	DM	
DBs:US Patents, US PGPUBS, USOCR, EPO,JPO,Derwent, IBM_TDB		2/28/2007	DM	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East see attached	. 2/28/2007	DM		
eDan Inventor Search	2/28/2007	DM		
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	2/28/2007	DM		
710/15-19,29,36-38 709/217-219,223- 226,238-239 370/248,329 714/25,40,43	2/28/2007	DM		
Google Patents	2/28/2007	DM		
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